Acta Crystallographica Section E Structure Reports Online

ISSN 1600-5368

# Frank Schaper and Hans-Herbert Brintzinger\*

Fakultät für Chemie, Universität Konstanz, Postfach 5560, 78434 Konstanz, Germany

Correspondence e-mail: hans.brintzinger@uni-konstanz.de

#### Key indicators

Single-crystal X-ray study T = 230 KMean  $\sigma(C-C) = 0.002 \text{ Å}$  R factor = 0.031 wR factor = 0.083 Data-to-parameter ratio = 11.4

For details of how these key indicators were automatically derived from the article, see http://journals.iucr.org/e. Tetrahydrothiophene tris(pentafluorophenyl)borane

In the title compound,  $(C_4H_8S)B(C_6F_5)_3$ , a comparatively long boron–sulfur distance of 2.0843 (16) Å is found, most probably due to the sterically demanding pentafluorophenylsubstituents. Bond distances and angles of the boron–aryl fragment are comparable to those found for uncoordinated  $MeB(C_6F_5)_3^-$  anions. Received 9 November 2001 Accepted 26 November 2001 Online 22 December 2001

# Comment

As a part of our investigations on the displacement of methylborate anions from zirconocene contact ion pairs, we have investigated the coordination of Lewis bases to tris-(pentafluorophenyl)borane for comparison. Single crystals of a Lewis base–Lewis acid adduct of tetrahydrothiophene and tris(pentafluorophenyl)borane were obtained by slow evaporation of a toluene solution containing the Lewis base and the Lewis acid in a ratio of approximately 1:1.



Bond distances and angles of the boron-aryl fragment  $[d_{B,C}]$ = 1.624 (2)–1.628 (2) Å,  $\alpha_{CBS}$  = 101.67 (9)–106.45 (10)°] are comparable to those found for uncoordinated methylborate anions MeB(C<sub>6</sub>F<sub>5</sub>)<sub>3</sub><sup>-</sup> [d<sub>B,C</sub> = 1.60–1.73 Å,  $\alpha_{C,B,Me} = 101–116^{\circ}$ (CSD; Allen & Kennard, 1993): BIQREY, BIQREY, CACVEH, CACVOR, CACWAE, CACXIN, CEWFAL, CEWFOZ, FEQDAG, GEGYUM, GEHFAA, GUCXAD, HIMJOC, HIWQIN, HOHYUY, KICYEA, NUWWIL, NUWWOR, POQVEW, POWTUQ, POWVAY, POZWIK, QAPGET, QAPGIX, QAPGOD, QAWZIX, QEMWUA, REZBIH, RIDYOS, RIDYUY, RIRLEJ, TOPBUV, WEMLAB, WEYHAJ, WILQAJ, WILQEN, WORJOC, WORJUI, WORKAP, YEKLEF, YUVPAG, ZAFQAY]. The boron-sulfur distance of 2.0843 (16) Å is the longest observed so far for the coordination of a thioether to a Lewis acidic boron centre [ $d_{B,S} = 1.82-2.07$  Å, 54 structures in the CSD (Allen & Kennard, 1993): BEGYIV, BUPBOD, CAFNUS, CHMSDB, CONBEM, DIMBEG10, DIMBOQ10, DONXIN, FEBROT, FIJNIV, FIJNOB, FIJPAP, GALZEY, GAMBUR,

Acta Cryst. (2002). E58, o77-o78

© 2002 International Union of Crystallography

Printed in Great Britain - all rights reserved



#### Figure 1

View of the title compound showing the labelling of non-H atoms. Displacement ellipsoids are shown at the 50% probability level.

GAMGOQ, GAMHIL, GAMHUX, GICDIF, GICDOL, JESWIN, KOMZAN, MOMSHB, NAQPIE, NEDLAJ, NITWUI, NITXAP, NORNEN, NUHCOI, NUHCUO, NUHDAV, PIBXED, PIBXIH, PIJTUX, PUCNAC, PUCNEG, RUHBOR, SOGMAC, TAJBEL, TAJBIP, TOJXUL, TOJYAS, TOJYEW, VEMVIS, VUYHIG, WARGAX, WARGEB, WARGIF, WICHAR, WICHEV, YAKCOC, YEDHUK, ZEJCAS, ZEKQEL, ZONVAZ], most probably due to the sterically demanding pentafluorophenyl substituents.

## **Experimental**

A toluene solution containing  $B(C_6F_5)_3$  and  $C_4H_8S$  in an approximately 1:1 ratio was slowly evaporated under an argon atmosphere over three weeks to yield colourless crystals of the adduct complex (I).

### Crystal data

 $C_{22}H_8BF_{15}S$  $M_r = 600.15$ Triclinic,  $P\overline{1}$ a = 9.5892 (8) Å  $b = 10.8264 (10) \text{\AA}$ c = 11.3959 (9) Å $\alpha = 111.904 \ (6)^{\circ}$  $\beta = 96.814 \ (7)^{\circ}$  $\gamma = 100.727 (7)^{\circ}$  $V = 1055.29 (16) \text{ Å}^3$ 

Z = 2 $D_r = 1.889 \text{ Mg m}^{-3}$ Mo  $K\alpha$  radiation Cell parameters from 42 reflections  $\theta = 11.3 - 12.4^{\circ}$  $\mu = 0.30 \text{ mm}^{-1}$ T = 230 KPrism, colourless  $0.6 \times 0.5 \times 0.3 \text{ mm}$ 

#### Data collection

Siemens P4 diffractometer	$\theta_{\rm max} = 27.0^{\circ}$
$\omega$ scans	$h = -10 \rightarrow 12$
Absorption correction: none	$k = -12 \rightarrow 12$
7694 measured reflections	$l = -14 \rightarrow 14$
4359 independent reflections	3 standard refle
3938 reflections with $I > 2\sigma(I)$	every 97 refl
$R_{\rm int} = 0.034$	intensity dec
	-

## Refinement

Refinement on  $F^2$  $R[F^2 > 2\sigma(F^2)] = 0.031$  $wR(F^2) = 0.083$ S = 1.054359 reflections 384 parameters All H-atom parameters refined

3	standard reflections
	every 97 reflections
	intensity decay: 1.8%
v	$\sigma = 1/[\sigma^2(F_o^2) + (0.0271P)]$
	$\pm 0.4601 P$

$w = 1/[\sigma(F_o) + (0.02/1P)]$
+ 0.4601P]
where $P = (F_o^2 + 2F_c^2)/3$
$(\Delta/\sigma)_{\rm max} = 0.001$
$\Delta \rho_{\rm max} = 0.28 \text{ e } \text{\AA}^{-3}$
$\Delta \rho_{\rm min} = -0.24 \text{ e } \text{\AA}^{-3}$

Table 1	
Selected	geometric parameters (Å, °).

S1-C19	1.8261 (15)	B1-C13	1.624 (2)
S1-C22	1.8286 (18)	B1-C7	1.628 (2)
S1-B1	2.0843 (16)	B1-C1	1.628 (2)
C13-B1-C7	115.42 (12)	C13-B1-S1	106.45 (10)
C13-B1-C1	113.86 (12)	C7-B1-S1	101.67 (9)
C7-B1-C1	112.10 (12)	C1-B1-S1	105.93 (9)

A relatively low data completeness (94.6%) was caused by the presence of a cooling device. The C-H bond lengths are 0.94 (2)-1.02 (2) Å.

Data collection: XSCANS (Siemens, 1992); cell refinement: XSCANS; data reduction: XSCANS; program(s) used to solve structure: SHELXS97 (Sheldrick, 1997); program(s) used to refine structure: SHELXL97 (Sheldrick, 1997); molecular graphics: SHELXTL-Plus (Siemens, 1991); software used to prepare material for publication: SHELXL97.

#### References

Allen, F. H. & Kennard, O. (1993). Chem. Des. Autom. News, 8, 31-37.

- Sheldrick, G. M. (1997). SHELXL97 and SHELXS97. University of Göttingen, Germany.
- Siemens (1991). SHELXTL-Plus. Release 4.1. Siemens Analytical X-ray Instruments Inc., Madison, Wisconsin, USA.

Siemens (1992). XSCANS. Siemens Analytical X-ray instruments Inc., Madison, Wisconsin. USA.